

<b>Notice of References Cited</b>	Application/Control No. 10/539,949	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Kimbinh T. Nguyen	Art Unit 2628	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,065,476	06-2006	Dessureault et al.	703/2
*	B	US-2005/0168460	08-2005	Razdan et al.	345/419
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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